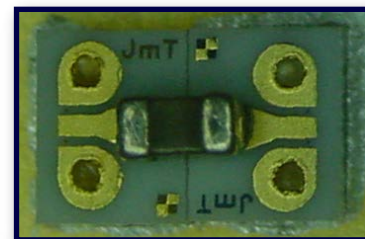
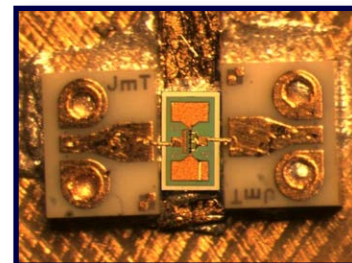
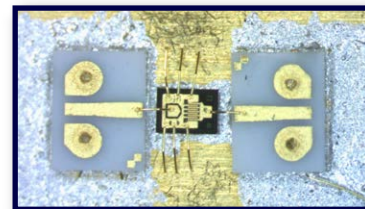


# Modelithics Probe Point™ Test Fixtures and Accessories

Modelithics is now offering **Probe-Point™ adapter substrates**, previously supplied by JMicro Technologies. These Alumina substrates adapt the benefits of coplanar waveguide RF wafer probe test methods testing microstrip formatted chips and circuits from DC through **70 GHz!** Along with this offering Modelithics is also offering custom coaxial and RF probe test fixtures suited for a wide range of substrate and test interface environments.

These components enhance productivity in product development and product assurance testing for semiconductors and packages. Some versions are available with series resistors to provide bias current stability. Calibration structures substrate and companion printed calibration kits are available for various adapter substrate configurations.

The products are test adapter and interface circuits. Each adapter circuit type primarily transforms a signal path from coplanar waveguide to microstrip transmission mode. Additional features of Series resistors and DC and signal sense are present on some product types. The products are ideal for testing GaAs/GaN as well as Silicon transistors, diodes and RFIC/MMIC die devices. Alumina Probe-Point™ substrate fixtures are available in 5, 10 and 15 mil thickness, making them compatible with a wide range of packages and high performance microwave semiconductors.



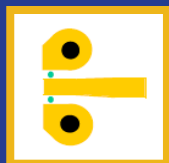
## 0503

### Features

- Compatible to coplanar probes 125μ to 250μ pitch
- Controlled impedance transition
- High quality backside vias

### Benefits

- High precision
- High repeatability
- High accuracy measurements
- Calibration structures available
- Low cost test tooling



Probe Point 0503

## 1003

### Features

- Compatible to coplanar probes 125μ to 250μ pitch
- Controlled impedance transition
- High quality backside vias

### Benefits

- High precision
- High repeatability
- High accuracy measurements
- Calibration structures available
- Low cost test tooling



Probe Point 1003

## 1503

### Features

- Compatible to coplanar probes 125μ to 450μ pitch
- Controlled impedance transition
- High quality backside vias
- Calibration Substrate available

### Benefits

- High precision
- High repeatability
- High accuracy measurements
- Calibration structures available
- Low cost test tooling



Probe Point 1503

## Modelithics Test Fixtures and Accessories

Modelithics is now offering **custom** RF probable and coaxial test fixtures with in-fixture calibration standards and associated calibration coefficient information. You can now avail yourself of the same test accessories and calibration techniques Modelithics has used for years to get precision measurements and models you trust!

### Probe Point Fixtures

- **0501, 1001\*** - Coplanar to Microstrip with a Kelvin sense point. The Kelvin sense point can be probed with a needle probe for DC voltage monitoring or with a G-S coplanar probe as a 20X signal sense point.
- **0502, 1002\*** - Coplanar to Microstrip with a Kelvin sense point. The Kelvin sense point can be probed with a needle probe for DC voltage monitoring or with a G-S coplanar probe as a 10X signal sense point.
- **0503, 1003, 1503** - Coplanar to Microstrip.
- **0504, 0505\*** - Load Chip
- **1505\*** - Coplanar to Microstrip with precision series resistor for bias stability.
- **0510, 0520, 0530\*** - Microstrip Transmission Lines

\*Availability of these products may be limited to legacy stock supplies and re-ordering may depend on customer volume requirements.

### Calibration Substrates

#### CM05, CM10, CM12, CM15

Calibration substrate for the test adapter and interface circuit products. This substrate contains the standards necessary to calibrate using any of the normally used techniques, including SOLT, TRL, LRM, LRL. All adapter circuit patterns are represented which allows direct precision calibration of the test environment.

**Calibration substrates are available for each Probe Point part size.**

### ProbePoint™ CM10 CPW-MSTRIP

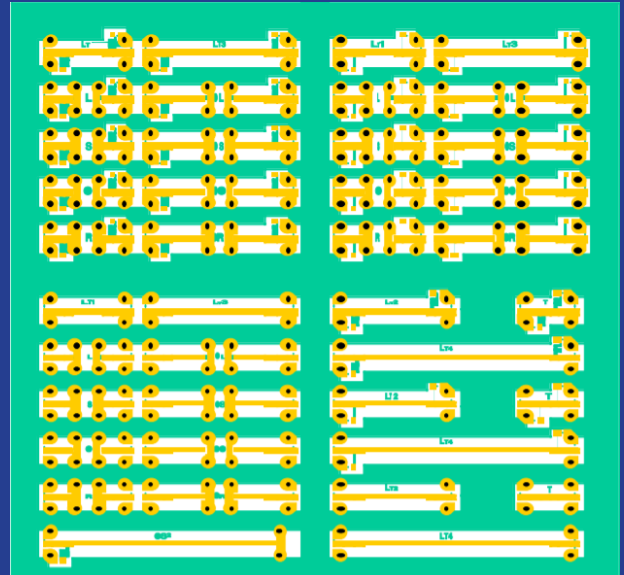
This substrate contains calibration structures to be used in the establishment of measurement corrections terms for measurements using network and time domain analysis. A variety of microwave structures which support the popular calibration methods are available for all the ProbePoint 10 Test Interface Circuits. This allows direct calibration to the microstrip bond pad side of the ProbePoint™ Test Interface Structures.

#### Features

- Compatible to coplanar probes - 125 $\mu$  to 250 $\mu$  pitch
- Flexible to various calibration methods: SOLT, LRM, LRL, TRL
- Laser trimmed resistors -  $\pm 1\%$
- Controlled impedance transition
- High quality backside vias

#### Benefits

- Direct Calibration
- High repeatability
- High accuracy calibration
- Low cost
- User flexibility



**To Request a Budgetary Quote, As Well As Volume Discounted Pricing, Contact the Modelithics Sales Team!**

**[Sales@Modelithics.com](mailto:Sales@Modelithics.com)**

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